SCOPE:

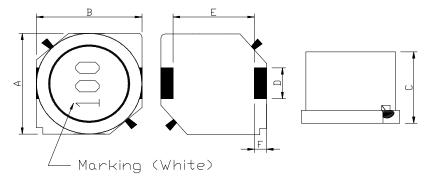
This specification applies to the Pb Free high current type SMD inductors for MSCDRI-75F-SERIES

PRODUCT INDENTIFICATION

MSCDRI - 75F - 4R7 M

- 1
- 2
- 3 4
- 1 Product Code
- 2 Dimensions Code
- **3 Inductance Code**
- **4** Tolerance Code

(1) SHAPES AND DIMENSIONS



A: 7.00±0.3 mm

B: 7.00±0.3 mm

C: 4.50±0.3 mm

D: 2.00±0.2 mm

E: 4.00Typ. mm

F: 1.50Typ. mm

(2) ELECTRICAL SPECIFICATIONS SEE TABLE 1

TEST INSTRUMENTS

L : HP 4284A PRECISION LCR METER (or equivalent)

RDC: CHROMA MODEL 16502 MILLIOHMMETER (or equivalent)

(3) CHARACTERISTICS

- (3)-1 Ambient temperature +60°C Max.
- (3)-2 Operate temperature range -40° C $\sim +125^{\circ}$ C (Including self temp. rise)
- (3)-2 Storage temperature range -40° C $\sim +125^{\circ}$ C

TABLE 1

MAGLAYERS	Inductance	Percent Test Resistance Rated DC Current		Moulsing			
PT/NO.	L(µH)	Tolerance	Frequency	RDC(Ω)±20%	IDC1(A)	IDC2(A)	Marking
MSCDRI-75F-1R0□	1.0	M,N	100kHz/0.5V	11m	4.50	4.50	1R0
MSCDRI-75F-3R3□	3.3	M,N	100kHz/0.5V	20m	2.50	2.30	3R3
MSCDRI-75F-4R7□	4.7	M,N	100kHz/0.5V	30m	2.00	2.10	4R7
MSCDRI-75F-6R8□	6.8	M,N	100kHz/0.5V	39m	1.70	1.74	6R8
MSCDRI-75F-100□	10	M,N	100kHz/0.5V	36m	1.30	1.78	100
MSCDRI-75F-150□	15	M,N	100kHz/0.5V	52m	1.10	1.53	150
MSCDRI-75F-220□	22	M,N	100kHz/0.5V	61m	0.90	1.34	220
MSCDRI-75F-330□	33	M,N	100kHz/0.5V	96m	0.82	1.09	330
MSCDRI-75F-470□	47	M,N	100kHz/0.5V	0.125	0.75	0.92	470
MSCDRI-75F-680□	68	M,N	100kHz/0.5V	0.175	0.60	0.77	680
MSCDRI-75F-101□	100	K,M	100kHz/0.5V	0.25	0.50	0.65	101
MSCDRI-75F-151□	150	K,M	100kHz/0.5V	0.34	0.40	0.55	151
MSCDRI-75F-221□	220	K,M	100kHz/0.5V	0.52	0.33	0.45	221
MSCDRI-75F-331□	330	K,M	100kHz/0.5V	0.74	0.25	0.37	331
MSCDRI-75F-471□	470	K,M	100kHz/0.5V	1.05	0.22	0.31	471
MSCDRI-75F-681□	680	K,M	100kHz/0.5V	1.48	0.20	0.27	681
MSCDRI-75F-102□	1000	K,M	100kHz/0.5V	2.28	0.14	0.25	102

※ □ specify the inductance tolerance,K(±10%),M(±20%),N(±30%)

% IDC1 : Based on inductance change (△L/Lo : \leq drop 15%) @ ambient temp. 25%

IDC2: Based on temperature rise (△T: 25°C TYP.)

Rated DC Current: The less value which is IDC1 or IDC2.



(4) RELIABILITY TEST METHOD

MECHANICAL

TEST ITEM	SPECIFICATION	TEST DETAILS				
Substrate bending	∆L/Lo≦±5%	The sample shall be soldered onto the printed circuit board				
		in figure 1 and a load applied unitil the figure in the arrow				
	There shall be	direction is made approximately 3mm.(keep time 30 seconds)				
	no mechanical	PCB dimension shall the page 7/9				
	damage or elec-	F(Pressurization)				
	trical damege.	,				
		R5 45±2 45±2 10 20 R340				
		PRESSURE ROD figure-1				
Vibration	∆L/Lo≦±5%	The sample shall be soldered onto the printed circuit board				
		and when a vibration having an amplitude of 1.52mm				
	There shall be	and a frequency of from 10 to 55Hz/1 minute repeated should				
	no mechanical	be applied to the 3 directions (X,Y,Z) for 2 hours each.				
	damage.	(A total of 6 hours)				
Solderability	New solder	Flux (rosin, isopropyl alcohol{JIS-K-1522}) shall be coated				
	More than 90%	over the whole of the sample before hard, the sample shall				
		then be preheated for about 2 minutes in a temperature of				
		130∼150℃ and after it has been immersed to a depth 0.5mm				
		below for 3±0.2 seconds fully in molten solder M705 with				
		a temperature of 245±5℃.				
		More than 90% of the electrode sections shall be couered				
		with new solder smoothly when the sample is taken out of				
		the solder bath.				



MECHANICAL

TEST ITEM	SPECIFICATION						
TEST ITEM Resistance to Soldering heat reflow soldering)	There shall be no damage or problems.	Temperature profile of reflow soldering 300 250 Reak temperature 200:30 10 sec 150 Pre-heating Slow cooling (Stored at room temperature) 2 min 100 2 min or mere The specimen shall be passed through the reflow oven with the condition shown in the above profile for 1 time. The specimen shall be stored at standard atmospheric conditions for 1 hour, after which the measurement shall be made.					

ELECTRICAL

TEST ITEM	SPECIFICATION	TEST DETAILS
Insulation	There shall be	DC 100V voltage shall be applied across this sample of top
resistance	no other	surface and the terminal.
	damage or	The insulation resistance shall be more than $1 \times 10^8 \Omega$.
	problems.	
Dielectric	There shall be	AC 100V voltage shall be applied for 1 minute acrosset the top
withstand	no other	surface and the terminal of this sample
voltage	damage or	
	problems.	
Temperature	∆L/L20°C ≦±10%	The test shall be performed after the sample has stabilized in
characteristics	0~2000 ppm/℃	an ambient temperature of -20 to +85 $^{\circ}\mathrm{C}$,and the value
		calculated based on the value applicable in a normal
		temperature and narmal humidity shall be △L/L20°C ≦±10%.



ENVIROMENT CHARACTERISTICS

TEST ITEM		SPECIFICATION						
High temperature	∆L/Lo≦±5%	The samp	The sample shall be left for 96±4 hours in an atmospere with					
storage		a tempera	a temperature of 85±2℃ and a normal humidity.					
	There shall be	Upon con	Upon completion of the measurement shall be made after the					
	no mechanical	sample ha	sample has been left in a normal temperature and normal					
	damage.	humidity	humidity for 1 hour.					
Low temperature	∆L/Lo≦±5%	The samp	The sample shall be left for 96±4 hours in an atmosphere with					
storage		a tempera	a temperature of -25±3℃.					
	There shall be	Upon con	Upon completion of the test, the measurement shall be made					
	no mechanical	after the s	samp	ole has been left in a no	rmal temperature and			
	damage.	normal hu	normal humidity for 1 hour.					
Change of	∆L/Lo≦±5%	The samp	The sample shall be subject to 5 continuos cycles, such as shown					
temperature		in the tab	in the table 2 below and then it shall be subjected to standard					
	There shall be	atmosphe	atmospheric conditions for 1 hour, after which measurement					
	no other dama-	shall be n	shall be made.					
	ge of problems							
			table 2					
				Temperature	Duration			
			1	−25±3° C	30 min.			
				(Themostat No.1)				
			2	Standard	No.1→No.2			
				atmospheric				
			3	85±2 ℃	30 min.			
				(Themostat No.2)				
			4	Standard	No.2→No.1			
				atmospheric				
Moisture storage	∆L/Lo≦±5%	The sample shall be left for 96±4 hours in a temperature of						
		40±2℃ and a humidity(RH) of 90~95%.						
	There shall be	hall be Upon completion of the test, the measurement shall be made after the sample has been left in a normal temperature and						
	no mechanical							
	damage.							
Test conditions :		<u> </u>		<u>-</u>				
	sample shall be reflo	w soldered o	onto	the printed circuit boar	d in every test.			

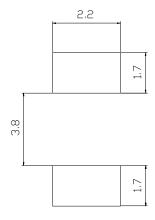


(5) LAND DIMENSION (Ref.)

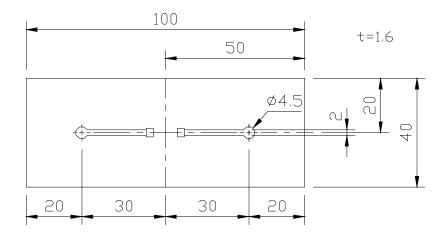
PCB: GLASS EPOXY t=1.6mm

(5)-1 LAND PATTERN DIMENSIONS

(STANDARD PATTERN) unit: mm



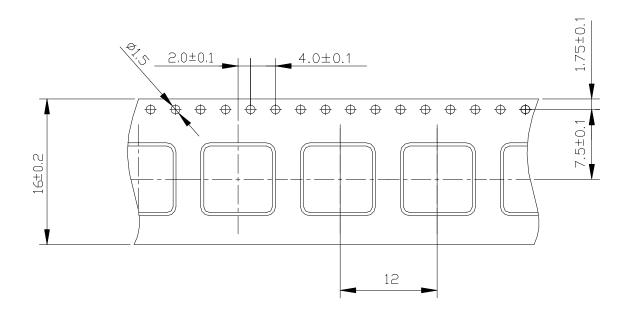
(5)-2 SUBSTRATE BENDING TEST BENDING TEST BOARD





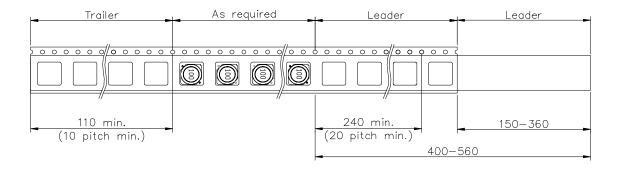
(6) PACKAGING

(6)-1 CARRIER TAPE DIMENSIONS (mm)

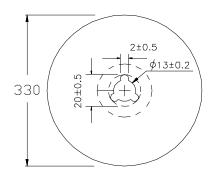


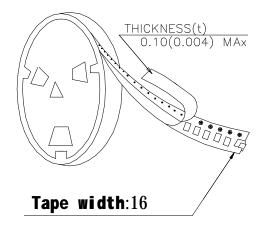
(6)-2 TAPING DIMENSIONS (mm)





(6)-3 REEL DIMENSIONS (mm)





(6)-4 QUANTITY

1000pcs/Reel

The products are packaged so that no damage will be sustained.